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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/607,185	PATTON ET AL.	
Examiner	Art Unit	
David C. Reese	3677	

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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Forward and backward citations from various hits from the listed search	6/13/2005	DR
Used past search (reference cited), prior art, etc, from parent case examined by Thomas Ho		
Text search under "near-field optics"		